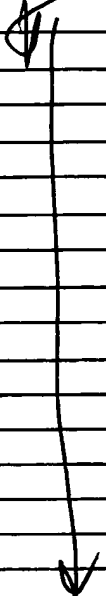




<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Attorney Docket No: <b>U.S.</b> LAM2P421 <b>10/607,613</b> Applicant: Kiermasz et al. Filing Date: <b>Group:</b> June 27, 2003 <b>3723</b>
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### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A	4,606,151	08/1986	Heynacher			
	B	4,850,152	07/1989	Heynacher et al.			
	C	5,575,707	11/1996	Talieh et al.			
	D	5,662,518	09/1997	James et al.			
	E	5,762,546	06/1998	James et al.			
	F	5,800,248	09/1998	Pant et al.			
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	H	5,888,126	03/1999	Hirose et al.			
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	O	6,135,858	10/2000	Takahashi			
	P	6,135,859	10/2000	Tietz			
Q	6,234,878	05/2001	Moore				

### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
[Handwritten Initials]	R	EP0920956	06/1999	EPO	[Handwritten Class]	[Handwritten Sub-class]	x	
	S	JP03259520	11/1991	JPO				x
	T	JP03259520	11/1991	Patent Abstracts of Japan			x	
	U	EP0881039	12/1998	EPO			x	
	V	FR2767735	08/1998	French Patent Office				x

### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	W	
	X	
	Y	
	Z	
Examiner <span style="float: right;">[Handwritten Signature]</span>		Date Considered <span style="float: right;">12/21/04</span>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	<b>Attorney Docket No:</b> U.S. LAM2P421 10/607,613  <b>Applicant:</b> Kiermasz et al.  <b>Filing Date:</b> Group: June 27, 2003 3723
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### U.S. Patent Documents

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<i>ds</i>	A2	6,062,959	05/2000	Weldon et al.	1	1	
<i>ds</i>	B2	6,103,628	08/2000	Talieh	1	1	
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						

### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	L							
	M							
	N							
	O							
	P							

### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	
	S	
	T	
Examiner	<i>[Signature]</i>	Date Considered <i>12/21/04</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.